Supporting Information

Title
Surface Chemistry and Restructuring in Thin-Film La_{n+1}Ni_{n}O_{3n+1} (n = 1, 2 and 3) Ruddlesden-Popper Oxides

K.-T. Wu,*abc H. Téllez, c J. Druce, c M. Burriel, ace F. Yang, d D. W. McComb, d T. Ishihara, bc J. A. Kilner,*ac and S. J. Skinner*au

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Figure S1 LEIS depth profiles of annealed (a) La_{3}Ni_{2}O_{7-δ} and (b) La_{4}Ni_{3}O_{10-δ} epitaxial films obtained from the LEIS yield of La/Ni cations and adsorbed contaminants (Na, S, P, K and Ca) using the 3 keV He+ analysis beam at the surface and near-surface region.